

Notice of References Cited	Application/Control No. 10/810,768	Applicant(s)/Patent Under Reexamination NILAND ET AL.	
	Examiner AARON J. LEWIS	Art Unit 3743	Page 1 of 3

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Notice of References Cited	Application/Control No. 10/810,768	Applicant(s)/Patent Under Reexamination NILAND ET AL.	
	Examiner AARON J. LEWIS	Art Unit 3743	Page 2 of 3

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	Examiner AARON J. LEWIS	Art Unit 3743	Page 3 of 3

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